



Product Change Notification / KSRA-18BGHS695

Date:

30-Sep-2021

Product Category:

Memory

PCN Type:

Manufacturing Change

Notification Subject:

CCB 4559 Final Notice: Qualification of SIGN as a new assembly site for selected SST39LFxxxx and SST39VFxxxx device families available in 48L TSOP (12x20mm) package.

Affected CPNs:

[KSRA-18BGHS695_Affected_CPN_09302021.pdf](#)
[KSRA-18BGHS695_Affected_CPN_09302021.csv](#)

Notification Text:

PCN Status:

Final notification

PCN Type:

Manufacturing Change

Microchip Parts Affected:

Please open one of the icons found in the Affected CPNs section.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change:

Qualification of SIGN as a new assembly site for selected SST39LFxx and SST39VFxx device families available in 48L TSOP (12x20mm) package.

Pre Change:

Assembled at LPI using 8340 die attach material and lead frame with paddle size 207x142mils, 183x161mils or 160x130mils.

Post Change:

Assembled at SIGN using AP-4300 die attach material and lead frame with paddle size 209x165mils or 159x165mils

Pre and Post Change Summary:

	Pre Change			Post Change		
Assembly Site	Lingsen Precision Industries, LTD. (LPI)			Signetics Corporation (SIGN)		
Bond Wire material	Au			Au		
Die Attach material	8340			AP-4300		
Mold compound material	G700			G700		
Lead frame material	C7025			C7025		
DAP Surface Prep	Ring/Selective			Ring/Selective		
Lead frame paddle size	207x142mils	183x161mils	160x130mils	209x165mils	159x165mils	
	See attached pre and post change comparison					

Impacts to Data Sheet:

None

Change Impact:

None

Reason for Change:

To improve on-time delivery performance by qualifying SIGN as a new assembly site.

Change Implementation Status:

In Progress

Estimated First Ship Date:

October 31, 2021 (date code: 2145)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Time Table Summary:

	February 2021					-->	September 2021					October 2021				
	06	07	08	09	10		36	37	38	39	40	41	42	43	44	45
Initial PCN Issue Date				X												
Qual Report Availability										X						
Final PCN Issue Date										X						

Estimated Implementation Date																				X
----------------------------------	--	--	--	--	--	--	--	--	--	--	--	--	--	--	--	--	--	--	--	---

Method to Identify Change:

Traceability code

Qualification Report:

Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History:

February 23, 2021: Issued initial notification.

April 14, 2021: Re-issued initial notification to change die attach material to AP-4300 in pre and post change and qual plan.

September 30, 2021: Issued final notification. Updated the lead frame DAP Surface Prep pre and post change to Ring/Selective. Attached the qualification report. Provided estimated first ship date to be on October 31, 2021.

The change described in this PCN does not alter Microchip’s current regulatory compliance regarding the material content of the applicable products.

Attachments:

[PCN_KSRA-18BGHS695_Qual_Report.pdf](#)

[PCN_KSRA-18BGHS695_Pre and Post Change_Summary.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to [receive Microchip PCNs via email](#) please register for our PCN email service at our [PCN home page](#) select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the [PCN FAQ](#) section.

If you wish to [change your PCN profile, including opt out](#), please go to the [PCN home page](#) select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

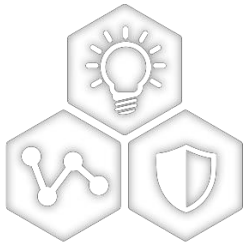
Affected Catalog Part Numbers (CPN)

SST39LF400A-55-4C-EKE
SST39VF400A-70-4C-EKE
SST39VF400A-70-4I-EKE
SST39LF400A-55-4C-EKE-T
SST39VF400A-70-4C-EKE-T
SST39VF400A-70-4I-EKE-T
SST39LF800A-55-4C-EKE
SST39VF800A-70-4C-EKE
SST39VF800A-70-4I-EKE
SST39VF800A-70-4I-EKE-TZ009
SST39VF800A-70-4C-EKE-T
SST39VF800A-70-4I-EKE-T
SST39VF1601-70-4C-EKE
SST39VF1602-70-4C-EKE
SST39VF1681-70-4C-EKE
SST39VF1682-70-4C-EKE
SST39VF1601-70-4C-EKE-PP013
SST39VF1601-70-4I-EKE
SST39VF1602-70-4I-EKE
SST39VF1681-70-4I-EKE
SST39VF1682-70-4I-EKE
SST39VF1601-70-4I-EKE-TZ009
SST39VF1601-70-4C-EKE-T
SST39VF1602-70-4C-EKE-T
SST39VF1681-70-4C-EKE-T
SST39VF1682-70-4C-EKE-T
SST39VF1601-70-4I-EKE-T
SST39VF1602-70-4I-EKE-T
SST39VF1681-70-4I-EKE-T
SST39LF200A-55-4C-EKE
SST39VF200A-70-4C-EKE
SST39VF200A-70-4I-EKE
SST39LF200A-55-4C-EKE-T
SST39VF200A-70-4C-EKE-T
SST39VF200A-70-4I-EKE-T
SST39VF3201B-70-4C-EKE
SST39VF3202B-70-4C-EKE
SST39VF3201B-70-4I-EKE
SST39VF3202B-70-4I-EKE
SST39VF3201B-70-4I-EKE-MCL
SST39VF3202B-70-4I-EKE-MCM
SST39VF3201B-70-4I-EKE-T

CCB 4559
Pre and Post Change Summary
PCN # KSRA-18BGHS695



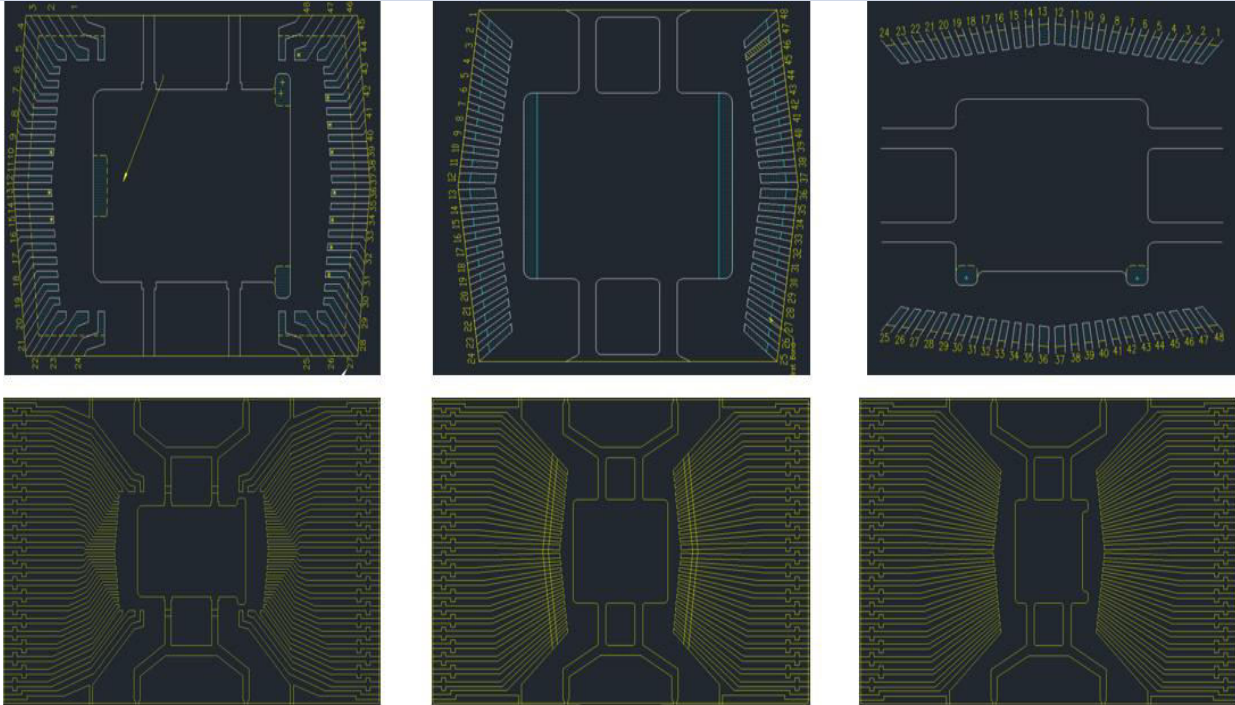
A Leading Provider of Smart, Connected and Secure Embedded Control Solutions



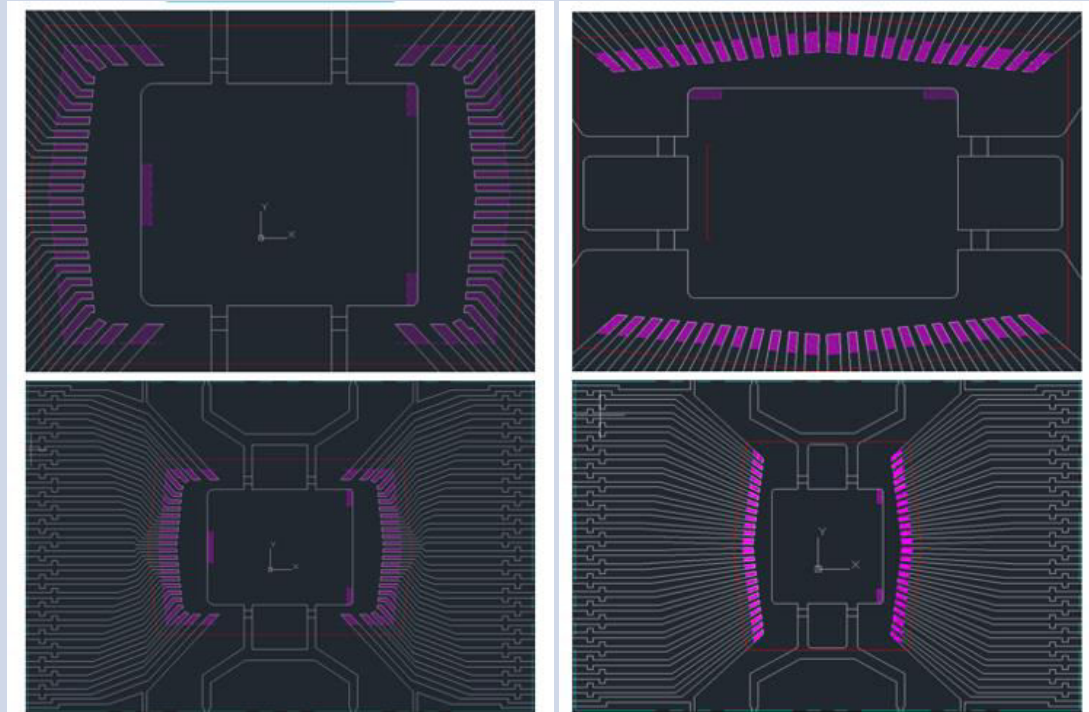
SMART | CONNECTED | SECURE

Lead frame Comparison

Pre Change
LPI



Post Change
SIGN





MICROCHIP

QUALIFICATION REPORT SUMMARY
RELIABILITY LABORATORY

PCN #: KSRA-18BGHS695

Date
September 21, 2021

**Qualification of SIGN as a new assembly site for selected
SST39LFxxxx and SST39VFxxxx device families available in
48L TSOP (12x20mm) package.**



MICROCHIP PACKAGE QUALIFICATION REPORT

Purpose Qualification of SIGN as a new assembly site for selected SST39LFxxxx and SST39VFxxxx device families available in 48L TSOP (12x20mm) package.

CCB No.	4559
CN	ES358575
QUAL ID	R2100642 Rev. A
MP CODE	X02057W9XM70
Part No.	SST39VF3201B-70-4I-EKE
Bonding No.	BDM-002852 Rev. B
<u>Package</u>	
Type	48L TSOP
Package size	12 x 20 mm
<u>Lead Frame</u>	
Paddle size	209 x 165 mils
Material	C7025
Surface	Ring / Selective Plating
Process	Stamped
Lead Lock	No
Part Number	FLF-00001
Treatment	Roughened
<u>Material</u>	
Epoxy	AP-4300
Wire	Au wire
Mold Compound	G700
Plating Composition	Matte Sn



MICROCHIP PACKAGE QUALIFICATION REPORT

Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
SIGN220200003.000	GC01919127814.100	2114KGK
SIGN220200004.000	GC01920463252.000	2114KGT
SIGN220200005.000	GC01921068944.000	2114KGV

Result

Pass Fail _____

48L TSOP (12x20 mm) assembled by SIGN pass reliability test per QCI-39000.
This package was qualified the Moisture/Reflow Sensitivity Classification Level 3 at 260°C
reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Precondition Prior Perform Reliability Tests (At MSL Level 3)	Electrical Test: +25°C, 95°C and -40°C System: NEXTEST_GV2X	JESD22-A113	693(0)	693	Pass	Good Devices
	Bake 150°C, 24 hrs System: CHINEE	JIP/IPC/JEDEC		693		
	30°C/60%RH Moisture Soak 192 hrs. System: TABAI ESPEC Model PR-3SPH	J-STD-020E		693		
	3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243			693		
	Electrical Test: +25°C and 95°C System: NEXTEST_GV2X			0/693		

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
Temp Cycle	Stress Condition: -65°C to +150°C, 500 Cycles System: TABAI ESPEC TSA-70H	JESD22-A104		231		Parts had been pre-conditioned at 260°C
	Electrical Test: +95°C System: NEXTEST_GV2X		231(0)	0/231	Pass	77 units / lot
	Bond Strength: Wire Pull (> 2.5 grams) Bond Shear (>15.00 grams)		15 (0)	0/15	Pass	
		15 (0)		0/15	Pass	
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22-A118		231		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C System: NEXTEST_GV2X		231(0)	0/231	Pass	77 units / lot
HAST	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: 3.6 Volts System: HAST 6000X	JESD22-A110		231		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C and 95°C System: NEXTEST_GV2X		231(0)	0/231	Pass	77 units / lot

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs System: SHEL LAB	JESD22-A103		45		45 units
	Electrical Test: +25°C and 95°C System: NEXTEST_GV2X		45(0)	0/45	Pass	
Solderability Temp 245°C	Steam Aging: Temp 93°C,8Hrs System: SAS-3000 Solder Dipping: Solder Temp.245°C Solder material: Pb Free Sn 95.5Ag3.9 Cu0.6System: ERSA RA 2200D Visual Inspection: External Visual Inspection	J-STD-002	22 (0)	22 22 0/22	Pass	
Physical Dimensions	Physical Dimension, 10 units from 1 lot	JESD22-B100/B108	30(0) Units	0/30	Pass	
Bond Strength Data Assembly	Wire Pull (> 3.00 grams)	Mil. Std. 883-2011	30 (0) Wires	0/30	Pass	
	Bond Shear (> 10.00 grams)	CDF-AEC-Q100-001	30 (0) bonds	0/30	Pass	